

Notice of References Cited	Application/Control No. 10/512,017	Applicant(s)/Patent Under Reexamination BENETIK ET AL.	
	Examiner Tsz K. Chiu	Art Unit 2822	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2003/0161091	08-2003	Devoe et al.	361/321.2
*	B US-6,366,443	04-2002	Devoe et al.	361/313
C	US-			
D	US-			
E	US-			
F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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